



(12) **EUROPEAN PATENT APPLICATION**

(88) Date of publication A3:
12.03.2003 Bulletin 2003/11

(51) Int Cl.7: **G11C 29/00, G11C 11/22**

(43) Date of publication A2:
03.07.2002 Bulletin 2002/27

(21) Application number: **01309870.2**

(22) Date of filing: **23.11.2001**

(84) Designated Contracting States:
**AT BE CH CY DE DK ES FI FR GB GR IE IT LI LU
MC NL PT SE TR**
Designated Extension States:
AL LT LV MK RO SI

(72) Inventor: **McClure, David C.**
Carrollton, Texas 75007 (US)

(74) Representative: **Style, Kelda Camilla Karen et al**
Page White & Farrer,
54 Doughty Street
London WC1N 2LS (GB)

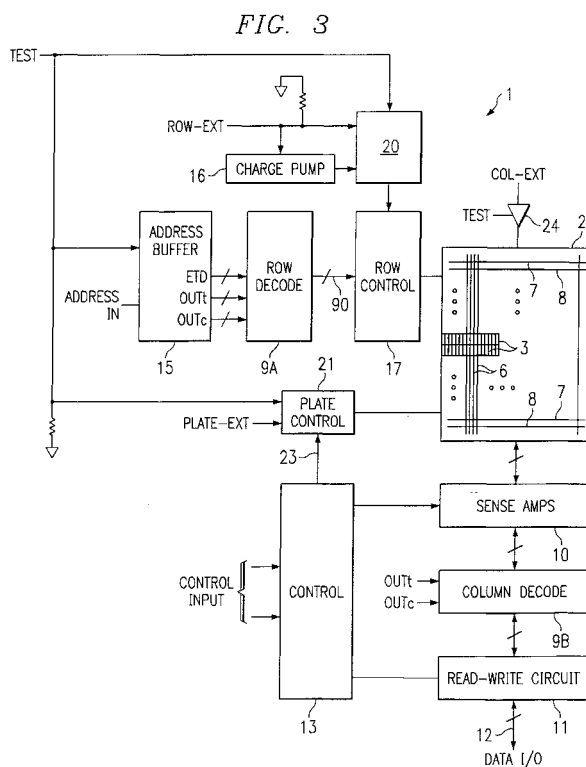
(30) Priority: **29.12.2000 US 751007**

(71) Applicant: **STMicroelectronics, Inc.**
Carrollton, TX 75006-5039 (US)

(54) **Circuit and method for performing a stress test on a ferroelectric memory device**

(57) A circuit and method for performing a stress test on a ferroelectric memory device. The memory device includes a memory cell array having a plurality of row lines, column lines and plate lines. The memory device further includes test circuitry for receiving at least one

test control signal and in response to the at least one test control signal allowing a voltage differential to be applied between the column lines and the plate lines, so that a stress voltage may be applied across each of the memory cells at one time.





European Patent
Office

EUROPEAN SEARCH REPORT

Application Number
EP 01 30 9870

DOCUMENTS CONSIDERED TO BE RELEVANT			
Category	Citation of document with indication, where appropriate, of relevant passages	Relevant to claim	CLASSIFICATION OF THE APPLICATION (Int.Cl.7)
X	US 6 055 200 A (CHOI MUN-KYU ET AL) 25 April 2000 (2000-04-25) * abstract; figures 1,4 * * column 3, line 30 - column 4, line 63 * ---	1-17	G11C29/00 G11C11/22
X	US 5 282 167 A (TANAKA HIROAKI ET AL) 25 January 1994 (1994-01-25) * abstract; figure 1 * * column 6, line 7 - line 57 * ---	9-17	
A		1-8	
X	US 6 046 926 A (TAKENAKA HIROYUKI ET AL) 4 April 2000 (2000-04-04) * abstract; figures 2,12 * * column 1, line 1 - column 5, line 19 * ---	1-17	
A	US 5 852 581 A (BEFFA RAY ET AL) 22 December 1998 (1998-12-22) * the whole document * -----	1-17	
			TECHNICAL FIELDS SEARCHED (Int.Cl.7)
			G11C
The present search report has been drawn up for all claims			
Place of search MUNICH		Date of completion of the search 15 January 2003	Examiner Ríos Báez, A
<p>CATEGORY OF CITED DOCUMENTS</p> <p>X : particularly relevant if taken alone Y : particularly relevant if combined with another document of the same category A : technological background O : non-written disclosure P : intermediate document</p> <p>T : theory or principle underlying the invention E : earlier patent document, but published on, or after the filing date D : document cited in the application L : document cited for other reasons & : member of the same patent family, corresponding document</p>			

EPO FORM 1503 03.82 (P04C01)

**ANNEX TO THE EUROPEAN SEARCH REPORT
ON EUROPEAN PATENT APPLICATION NO.**

EP 01 30 9870

This annex lists the patent family members relating to the patent documents cited in the above-mentioned European search report.
The members are as contained in the European Patent Office EDP file on
The European Patent Office is in no way liable for these particulars which are merely given for the purpose of information.

15-01-2003

Patent document cited in search report		Publication date		Patent family member(s)	Publication date
US 6055200	A	25-04-2000	KR	2000031586 A	05-06-2000
			JP	2000149596 A	30-05-2000
			TW	436785 B	28-05-2001

US 5282167	A	25-01-1994	JP	2829135 B2	25-11-1998
			JP	4230048 A	19-08-1992
			KR	9600889 B1	13-01-1996

US 6046926	A	04-04-2000	JP	11120797 A	30-04-1999

US 5852581	A	22-12-1998	US	5898629 A	27-04-1999
